

# PATENT ABSTRACTS OF JAPAN

(11)Publication number : 06-082238

(43)Date of publication of application : 22.03.1994

(51)Int.Cl. G01B 11/24  
G01B 11/03  
G01B 21/20

(21)Application number : 04-231672 (71)Applicant : TOSHIBA CORP

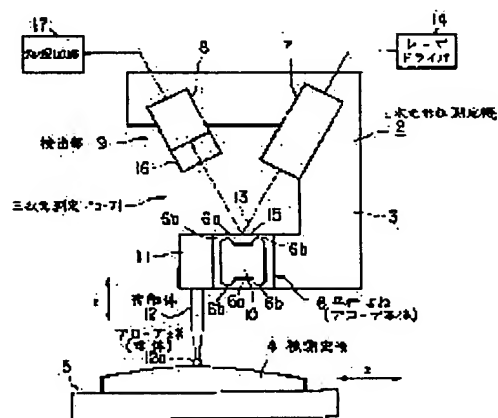
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## (54) THREE-DIMENSIONAL MEASURING PROBE

### (57)Abstract:

PURPOSE: To provide a three-dimensional measuring probe with a high measuring accuracy without damaging an object.

CONSTITUTION: This apparatus includes a parallel spring 6 deformable elastically, a contact body 12 which is mounted on the parallel spring 6 and moves having a probe ball 12a at the tip thereof while keeping the probe ball 12a in contact with an object 4 to deform the parallel spring 6 elastically according to irregularities of the surface of the object 4 and a detecting section 9 to detect a deformation value of the parallel spring 6 in an optical lever manner.



## LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against]

examiner's decision of rejection]  
[Date of extinction of right]

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